2. Regression and Classification

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regression and classification

regression in ML:

- estimation of a <u>continuous</u> <u>variable</u>, y, from data x in a training set
- examples: linear, kernel, Gaussian Process

kernel regression

classification in ML:

- estimation of a <u>categorical</u> <u>variable</u>, y, from data x in a training set
- examples: k-nn, logistic,
 SVM, trees, random forest





what is regression?

regression in ML:

- estimation of a continuous variable, y, from data x in a training set
- ex.: photo-z estimation from galaxy colors

 model: y = f(x;w) + ε
 w: model parameters
 ε: error or noise

we need:

- loss/cost function l(w): to evaluate the quality of model fitting
- optimizer: find w by minimization of the loss function

noise:

models do not fit the data perfectly:

model: $y = f(x;w) + \varepsilon$ ε : error or noise

- ε can be due to measurement errors in x and/or y
- ε can be due to the inadequacy of the model (too simple, too complicate)

example: ordinary linear regression

- linear model (in the parameters!): y = w₀+w₁x parameters: {w₀,w₁}
- cost/loss function: sum of the squares of the residuals

$$\mathbf{l}(\mathbf{w}) \propto \chi^2 \propto \Sigma_{i=1}^{\mathbf{N}} \left[\mathbf{y}_i - \left(\mathbf{w_0} + \mathbf{w_1} \mathbf{x}_i \right) \right]^2$$

- optimization: minimization of the least squares
- ML main optimizer: gradient descent

learning/optimization with gradient descent

optimization of the cost/loss l(w):

 $\mathbf{l}(\mathbf{w}) \propto \chi^{2} \propto \Sigma_{i=1}^{N} \left[\mathbf{y}_{i} - \left(\mathbf{w}_{0} + \mathbf{w}_{1}\mathbf{x}_{i}\right)\right]^{2}$

- initialization: random values for w
- Iearning based on the gradient:

update of w: $w \leftarrow w - \lambda \partial I(w) / \partial w$

 λ : 'learning rate'



for a single datum:

- w ← w + 2λ [y_i y(x_i;w)]
 [...] is the residual with the current value of the parameters w
- as the training proceeds, it decreases and (hopefuly!) converges to a stationary value

optimization strategies:

- batch: update w after presentation of all data
- mini-batch: update w with n random objects
- stochastic: update w after each object

learning/optimization with gradient descent

example: linear regression
 A (semi-major axis) x r_auto

 $W \leftarrow W + 2\lambda [y_i - y(x_i; w)]$



models and generalization

models should have the 'right' complexity (or 'capacity'):

- models too simple: underfitting
 models too complex: overfitting
 - → the models fit the noise!
- example: fitting of a polynomium of degree M
- the polynomium is fitted with the training set and then applied to a test set









what happens for high values of M?

• the models fits the noise: w 'explode'!



- example: weights for M = 9
 30.87, -1122.61, 13019.71, -75589.66, 256956.84, -544754.35, 730907.60, -603984.86, 280679.44, -56144.84
- a way to prevent overfitting: '<u>regularization</u>' it constrains the size of the weigths



regularization with a new term in the cost function

• $I(w) = \chi^2 / 2 + \alpha w^T.w$

α: regularization parameter

- the additional term penalizes large absolute values of w
- linear model: "ridge regression" w = (x^Tx+αI)⁻¹x^Ty
- gradient descent for a single datum: w = w + $2\lambda [y_i - y(x_i;w) - \alpha w]$

LASSO: least absolute shrinkage and selection

 $I(w) = \chi^2 / 2 + \alpha |w|$

notice that OLS is a particular case of ridge regression and LASSO



kernel regression

K(u): kernel h: bandwidth

$$\begin{split} \mathbf{y} &= \mathbf{f}(\mathbf{x}|\mathbf{K}) = \frac{\sum_{i=1}^{N} \mathbf{K} \left(|\mathbf{x} - \mathbf{x}_{i}| / \mathbf{h}\right) \mathbf{y}_{i}}{\sum_{i=1}^{N} \mathbf{K} \left(|\mathbf{x} - \mathbf{x}_{i}| / \mathbf{h}\right)} = \\ &= \sum_{i=1}^{N} \mathbf{w}_{i}(\mathbf{x}) \mathbf{y}_{i} \end{split}$$

kind of "local regression": weighted mean of y with weights

$$\mathbf{w}_{i}(\mathbf{x}) = \frac{\mathbf{K}\left(|\mathbf{x} - \mathbf{x}_{i}|/\mathbf{h}\right)\mathbf{y}_{i}}{\sum_{i=1}^{N}\mathbf{K}\left(|\mathbf{x} - \mathbf{x}_{i}|/\mathbf{h}\right)}$$

- many variants: locally linear regression, locally polynomial regression, adaptive kernel
- h can be determined by crossvalidation





Gaussian Process (GP) regression

modeling of functions:

parametric scenario: $y = f(x;w) + \varepsilon$

- the functional for f is assumed known
- regression: estimation of the parameters w

functional space scenario: $f \sim GP(\mu,k)$

- f is assumed sampled from a "functional space"
- regression: estimation of the posterior of the values of the functions at the points of interest

• Gaussian distribution vector sampling: $f = \{f_1...f_N\} \sim N(\mu, \Sigma)$

GP- function sampling: f(x) ~ GP(m(x),k(x,x')

GP is a Gaussian process of mean m = E(f(x)) and covariance k(x,x')



- GP: f(x) ~ GP(m(x),k(x,x')
- example: radial basis functions

$$\mathbf{k}(\mathbf{x}, \mathbf{x}') = \sigma^2 \exp\left(-\frac{|\mathbf{x} - \mathbf{x}'|}{2\lambda^2}\right)$$

main hyperparameters:
 λ controls the horizontal scale
 σ controls the vertical scale



problem: matrix inversions α N³
 solution: sparse approximation of the data

(deep GP: a GP that is a function of another GP)



cross-validation

- estimation of "model errors" and/or of model hyperparameters
- simple CV: estimate model reliability with a test set

Training	Training	Training	Validation	Testing
Training	Training	Validation	Training	Testing
Training	Validation	Training	Training	Testing
Validation	Training	Training	Training	Testing

K-fold CV:

- data is divided in K+1 subsamples
- train K models and let one subsample aside to measure their errors
- errors in the model can be estimated from the median of the errors in each subsample
- hyperparameters can be chosen by K-fold CV plus grid search



Classification

what is classification?

- sample of N objects with D features x
- objective: to <u>determine the label or</u> <u>class</u> of the object

Examples:

- Hubble types: E, S0, Sbc...
- BPT types: SF, Sey1, LINERs, transition
- detected/non-detected
- Star/galaxy
- 0/1



- the data features can be real or categorical
- classification: we train a function with a training and validation sets







what is classification?

classification: binary or multiclass

Problems:

- classes are often not cleanly separable
- <u>imbalance</u> in the training set: very different numbers of objects in each class
 - \rightarrow bias toward the majority class!



cost 0/1: we give 0 to a correct classification and 1 to a wrong one

If \hat{y} is the estimate of y:

$$\mathbf{L}(\mathbf{y}, \mathbf{\hat{y}}) = \begin{cases} 1 & \mathbf{if} \ \hat{y} \neq y \\ 0 & \mathbf{if} \ \hat{y} = y \end{cases}$$

classification risk (= error rate): E[L(y, \hat{y})] = prob(y $\neq \hat{y}$)

• cross-entropy (multiclass):

$$CE(\mathbf{y}, \mathbf{\hat{y}}) = -\frac{1}{N} \Sigma_{i=1}^{N} \left[\mathbf{y}_{i} \log \mathbf{\hat{y}}_{i} + (1 - \mathbf{y}_{i}) \log(1 - \mathbf{\hat{y}}_{i}) \right]$$

cost function

mean square error:

$$\frac{1}{N}\!\!\sum_{i=1}^{N}\left(\mathbf{\hat{y}}_{i}-\mathbf{y}_{i}\right)^{2}$$





binary classification: completeness and contamination

- detection (1) non-detection (0)
- completeness (recall): fraction of detections

$$\mathbf{R} = \frac{\mathbf{IP}}{\mathbf{TP} + \mathbf{FN}}$$

contamination: fraction of wrong detections

$$\frac{\rm FP}{\rm TP+FP}$$

accuracy: fraction of correct detections

 $\frac{\mathbf{TP}+\mathbf{TN}}{\mathbf{TP}+\mathbf{TN}+\mathbf{FP}+\mathbf{FN}}$

error rate (misclassification)

 $\frac{\mathbf{FP} + \mathbf{FN}}{\mathbf{TP} + \mathbf{TN} + \mathbf{FP} + \mathbf{FN}}$

precision (positive predictive value)
 = 1-contamination

$$\mathbf{P} = \frac{\mathbf{T}\mathbf{P}}{\mathbf{T}\mathbf{P} + \mathbf{F}\mathbf{P}}$$

F₁ score: harmonic mean of precision and completeness

$$\mathbf{F_1} = \mathbf{2}\frac{\mathbf{P} \times \mathbf{R}}{\mathbf{P} + \mathbf{R}}$$

Depending of the problem we may want to optimize the completeness, or the accuracy, or the precision...



Classification with k nearest neighbors (k-NN)

- adopt the class of the nearest neighbor in the training set
- the decision limits between classes form a Voronoi Tesselation

variants:

- adopt the most frequent class among k nearest neighbors in the training set
- weight by the neighbor distance

(method sensitive to the definition of distance)

k can be obtained by CV

classification with logistic regression

- Classification in two classes: 0 or 1
- probability of class 1 for a certain object:

$$\mathbf{p}(\mathbf{y} = \mathbf{1} | \mathbf{x}_i) = \mathbf{S}(\boldsymbol{\Sigma}_j \mathbf{w}_j \mathbf{x}_{ij}) = \mathbf{f}(\mathbf{x} | \mathbf{w})$$

S(x): sigmoid or logistic function

$$S(x) = rac{1}{1 + e^{-x}}$$
 $0 < S(x) < 1$





classification with logistic regression

- Classification in two classes: 0 or 1
- probability of class 1 for a certain object:

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S(x): sigmoid or logistic function

$$S(x) = \frac{1}{1 + e^{-x}}$$
 $0 < S(x) < 1$

cost function:

since y is binary, the cost can be modelled as a Bernoulli function:

$$\mathbf{l}(\mathbf{w}) = \prod_{i=1}^{N} \mathbf{p}_i(\mathbf{w})^{\mathbf{y}_i} (\mathbf{1} - \mathbf{p}_i(\mathbf{w}))^{\mathbf{1} - \mathbf{y}_i}$$

w is obtained by minimazing I(w),i.e., the classification error





classification with SVM support vector machine

- margin: hyperplane which maximizes the distance to the closest points of other classes
- the concept applies even when different classes overlap each other
- points in the margin define the support vectors
- to reduce contamination in the data space, SVM transforms the data to a higher dimensional space
- this is done using kernels (the "kernel trick")



classification with SVM support vector machine

- SVM is less sensitive to imbalance than other methods
- can achieve high completeness but with high contamination





classification with decision trees

- decision trees: nodes, branches, leaves
- the top node contains all data
- at each level of the tree the nodes are divided in two (or more) branches
- the divisions are based on decision limits: values above the limit go to a branch, and values below the limit to the other branch
- the divisions proceed until a convergence criterion is achieved

- the terminal nodes- *leaves* register the fraction of data points within each class
- classification of a leave: majoritary class
- classification of a new datum: follow the branches through binary decisions until arriving in a leave



classification with decision trees

- complexity of the tree: number of levels, or depth
- controling the tree growth may be necessary to avoid overfitting
- tree pruning: use CV to remove nodes that do not contribute much to the result





classification with random forest

random forest: type of *ensemble learning:* combination of results of several models

- generates many decision trees, each using only a subset of the data features
- the final classification is the mean of the classifications of the decision trees
- parameters: n- number of trees and m- number of features per tree
- m small reduces overfitting and improves predictivity
- n and m can be obtained by CV



comparison of classifiers

algorithm	accuracy
logistic regression	89.6
decision trees	90.4
\mathbf{SVM}	92.8
kNN	98.2
random forests	98.5

caution: no free lunch theorem!



